

**Notice of References Cited**

Application/Control No.

10/784,984

Applicant(s)/Patent Under

Reexamination

DUNK, CRAIG ALLAN

Examiner

Oanh Duong

Art Unit

2155

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0177228 A1	09-2003	Vigouroux et al.	709/224
*	B	US-6,006,259 A	12-1999	Adelman et al.	709/223
*	C	US-2004/0052225 A1	03-2004	Lundstrom, Johan	370/329
*	D	US-2004/0001474 A1	01-2004	Simelius et al.	370/349
*	E	US-2003/0105850 A1	06-2003	Lean et al.	709/223
*	F	US-6,761,636 B2	07-2004	Chung et al.	463/42
*	G	US-2002/0152446 A1	10-2002	Fleming, Roger A.	714/815
*	H	US-2004/0044771 A1	03-2004	Allred et al.	709/227
*	I	US-2004/0143665 A1	07-2004	Mace et al.	709/227
*	J	US-5,699,511 A	12-1997	Porcaro et al.	714/55
*	K	US-2004/0205189 A1	10-2004	Sata et al.	709/225
*	L	US-2003/0221010 A1	11-2003	Yoneya et al.	709/227
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.